

I0-TPI

Using Full Wave Solvers for Practical Analysis of Capacitor Mounting Structures

Scott McMorrow, Teraspeed Consulting Group LLC

Steve Weir, Teraspeed Consulting Group LLC

Fabrizio Zanella, CST of America



Outline

- o MLCC Basics
- o MLCC Full Wave Modeling
- o Measurements of Capacitor Test Fixture
- o Correlation between Modeling and Measurements
- o Conclusion

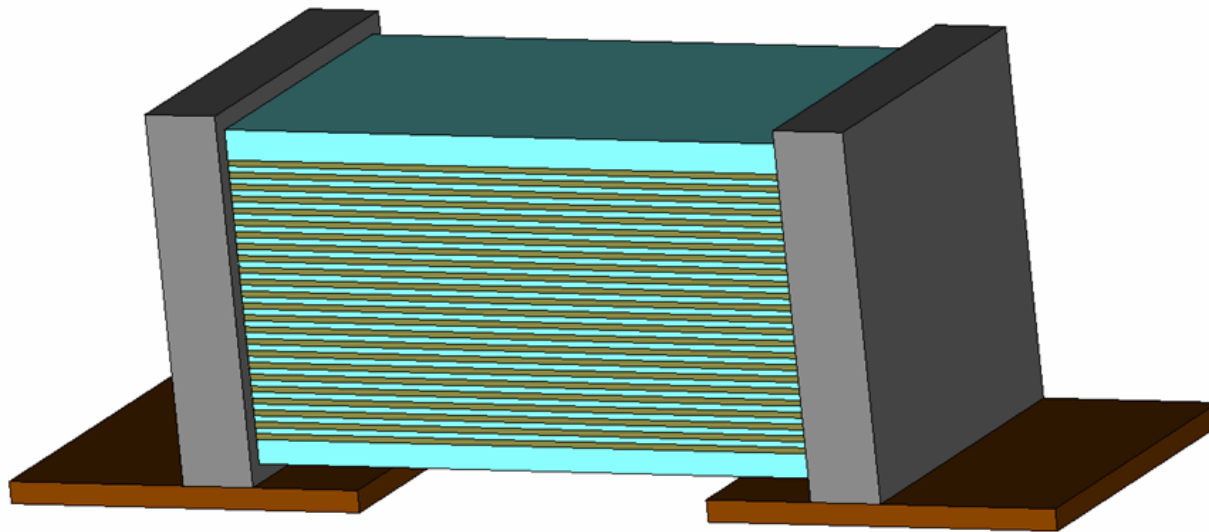


MLCC Capacitor Advantages

- o Larger capacitance values
- o Lower ESR, ESL, and Z than conventional capacitor designs
- o Cost effective designs



MLCC Capacitor Design



MLCC capacitor with fully populated plates



MLCC Capacitor Basics

MLCC capacitor: 2 sets of inter-leaved electrodes

$$C = \frac{(K) (n) (A)}{(d)}$$

C = capacitance value

K = dielectric constant

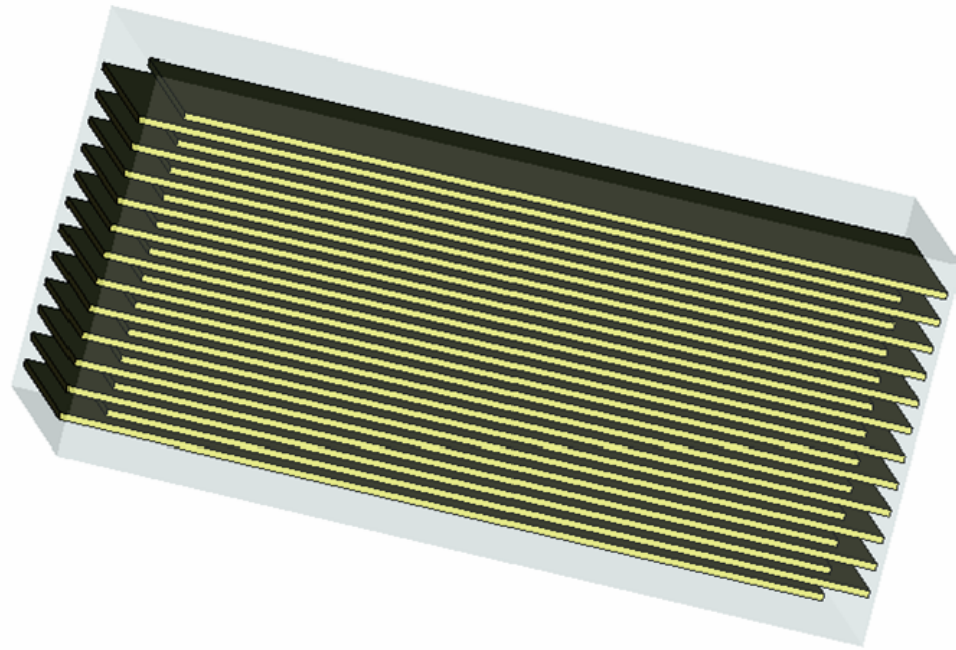
n = number of layers (n + 1 electrodes)

A = area of electrode overlap (figure 2)

d = dielectric thickness (between layers)



MLCC Capacitor Design

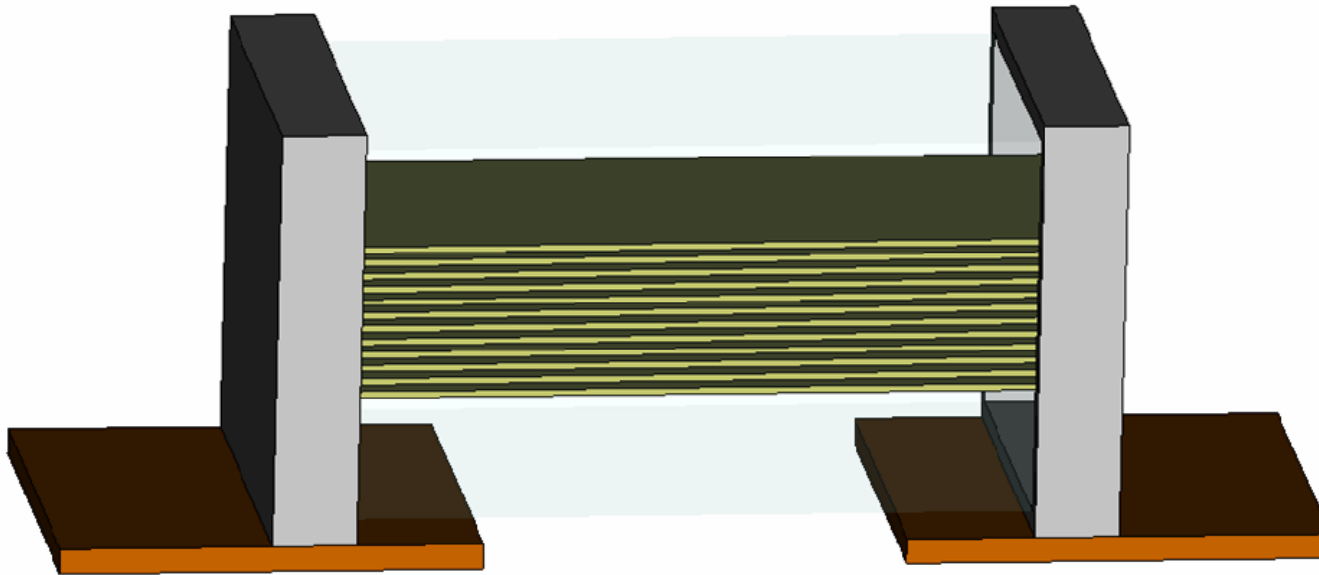


Material	Tin
Type	Lossy metal
Mue	1
El. cond.	8.7e+006 [S/m]

MLCC electrodes, showing plate overlap



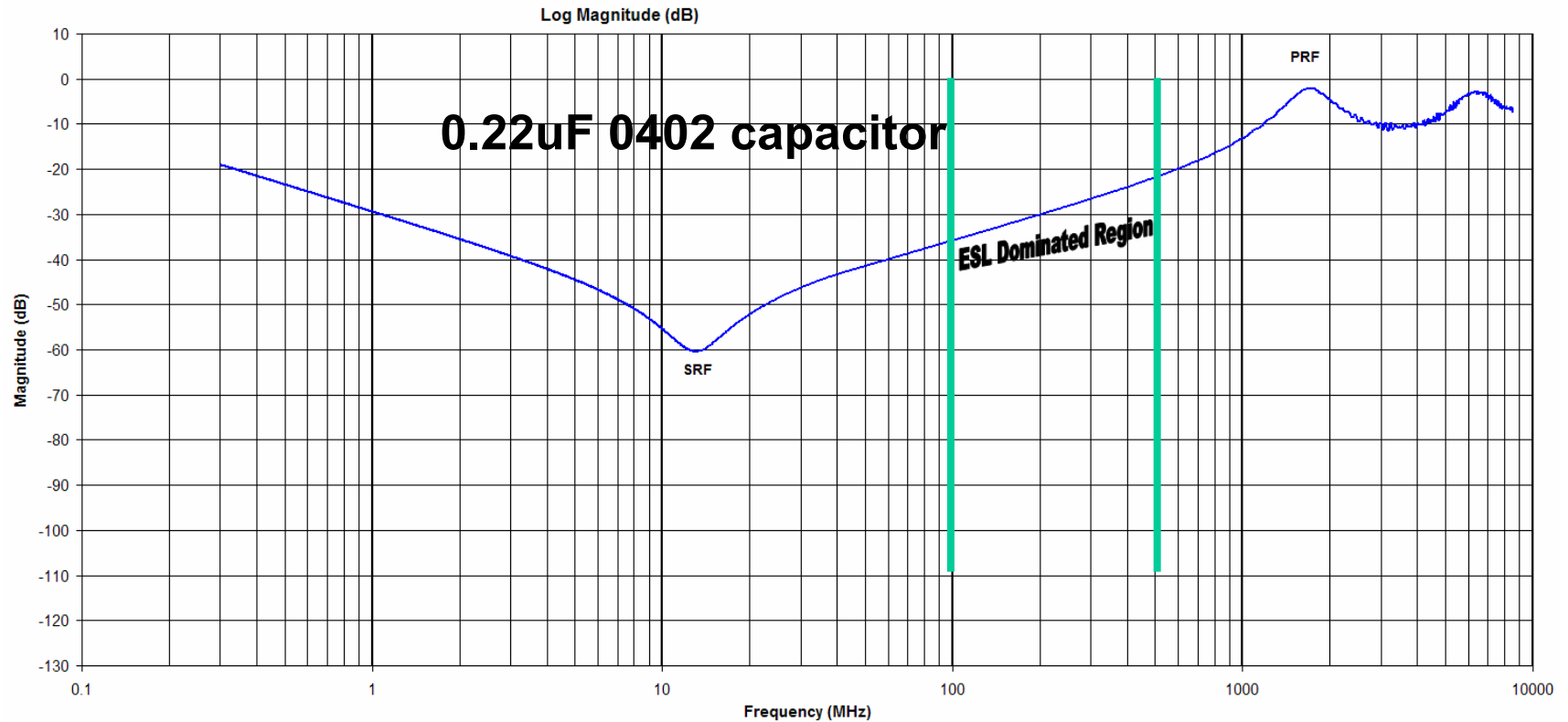
MLCC Capacitor Design



Only part of capacitor body used, larger capacitance value possible by increasing number of plates



Capacitor Transfer Impedance Measurement



$$Z_{ESL} = j\omega ESL$$

$$Z_{ESL} = 2\pi f \times ESL$$

$$ESL = Z_{ESL} / 2\pi f$$

$$ESL = (25 * S_{21}(\text{mag}) / (1 - S_{21}(\text{mag}))) / 2\pi f$$

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Capacitor Inductance Measurement

MLCC capacitor: 2 sets of inter-leaved electrodes

$$C = \frac{(K) (n) (A)}{(d)}$$

C = capacitance value

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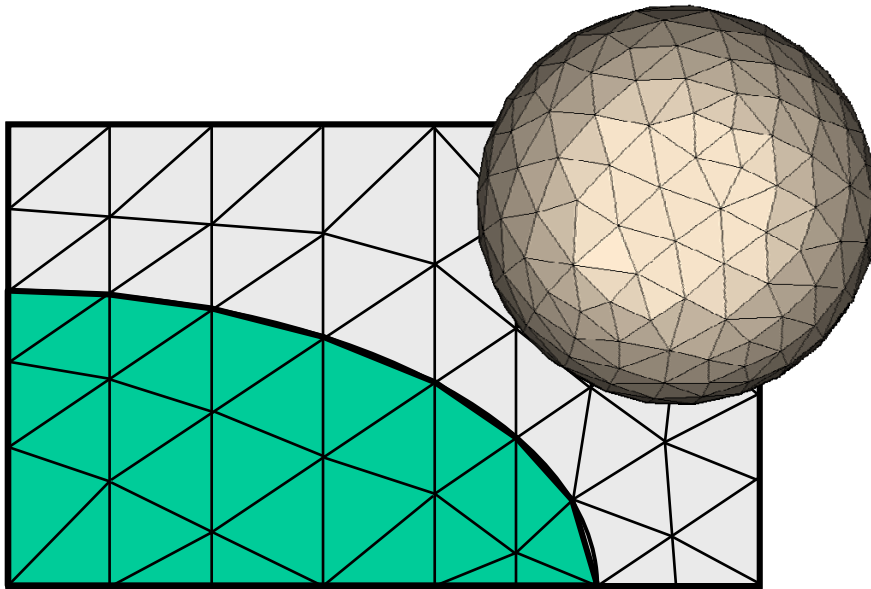
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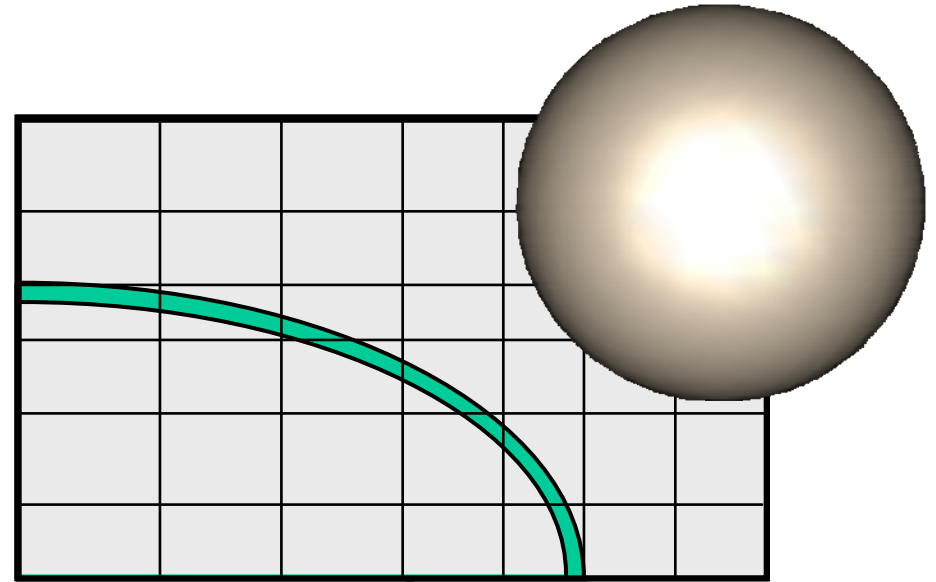


3D Full Wave Modeling



TET-Mesh in Freq. Domain

- ☺ Push Button Solution
- ☺ Electrically small structures
- ☺ Arbitrary material dispersion



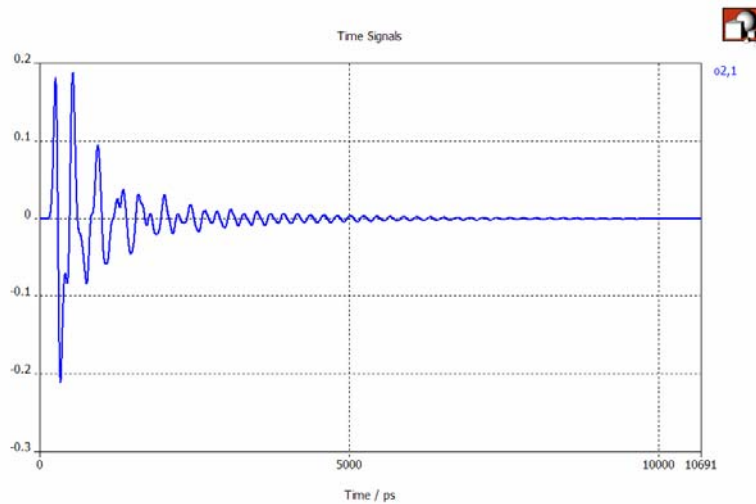
PBA-Mesh in Time Domain

- ☺ Electrically large structures
- ☺ Low memory
- ☺ Broadband Solution

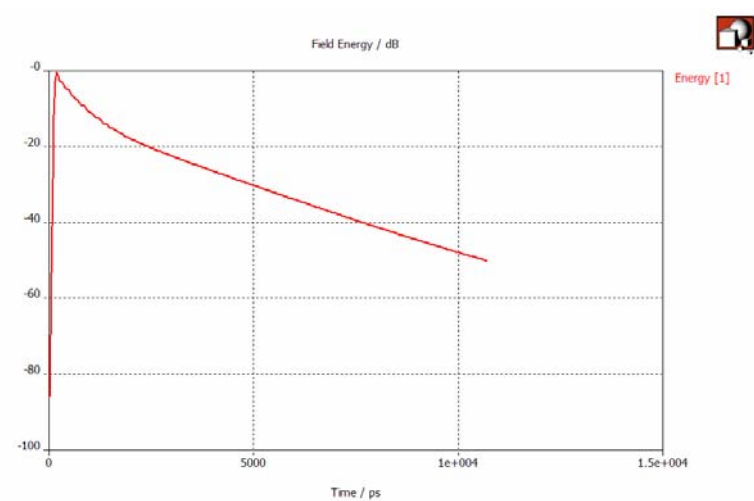


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Transient Solver



Transient Response Port 1 to Port 2

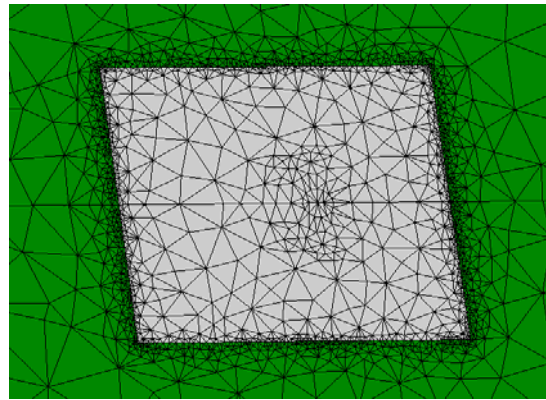


Solver Energy

- Begin with no energy inside calculation domain
- Inject energy and step through time
- Hexahedral meshing
- When energy decays “far enough,” the simulation stops



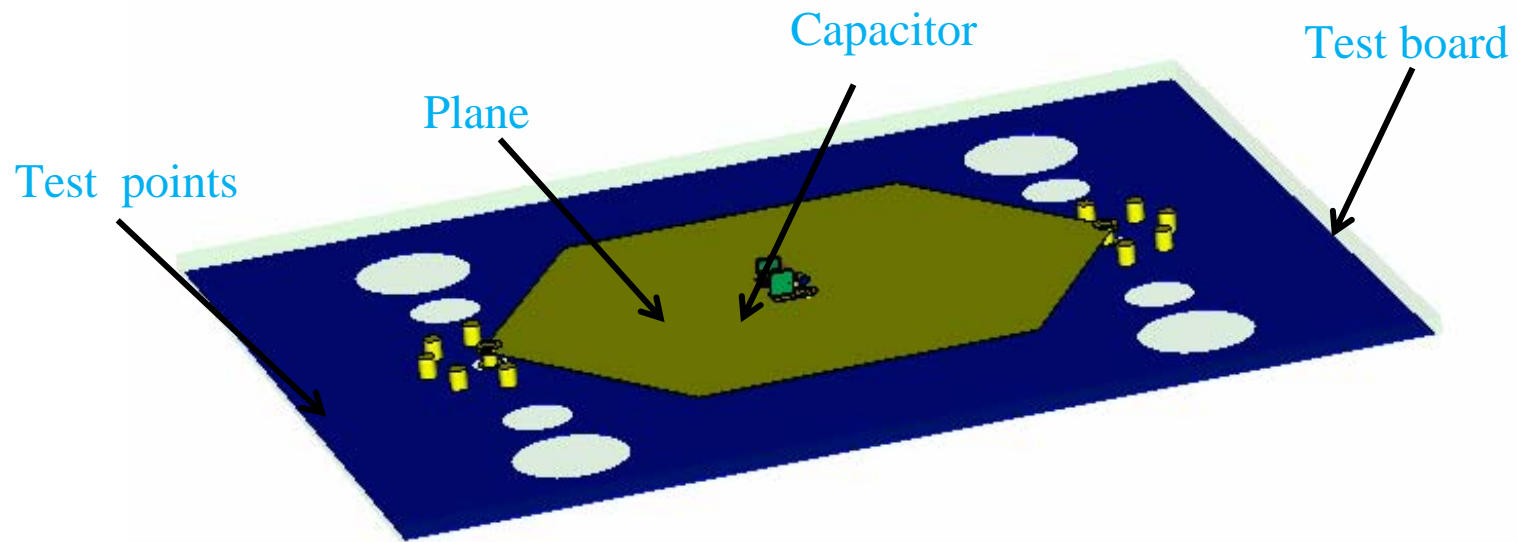
Frequency Domain Solver



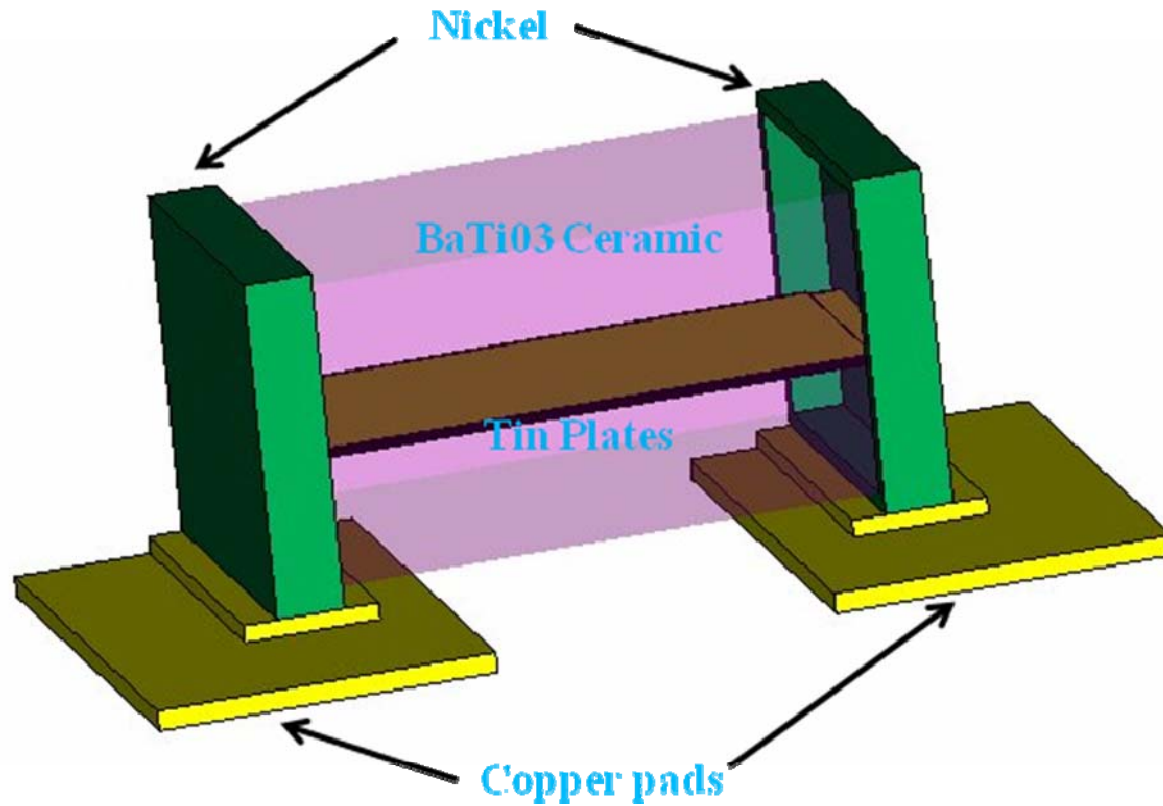
- Simulation performed at single frequencies
- Broadband Frequency Sweep to achieve accurate S-Parameters
- Well suited applications: Narrowband, electrically small structures



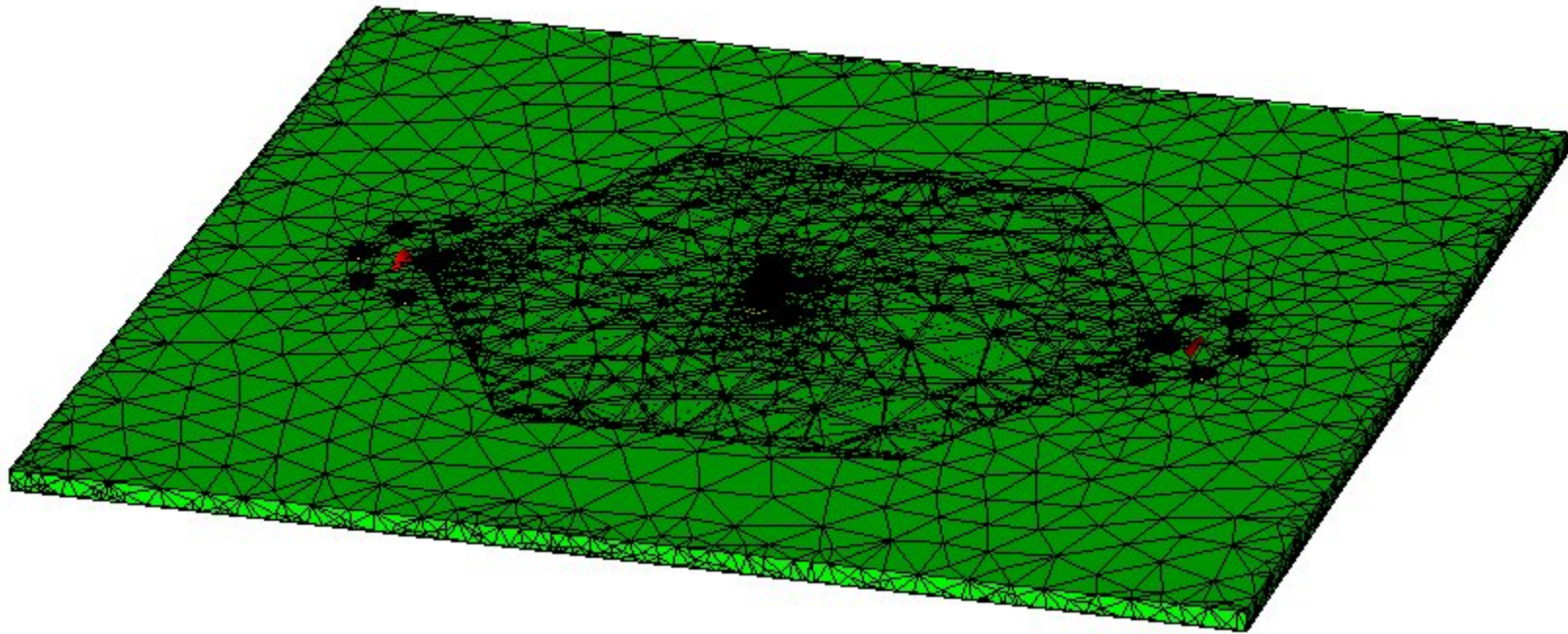
Capacitor Test Fixture Model



MLCC Capacitor Full Wave Model



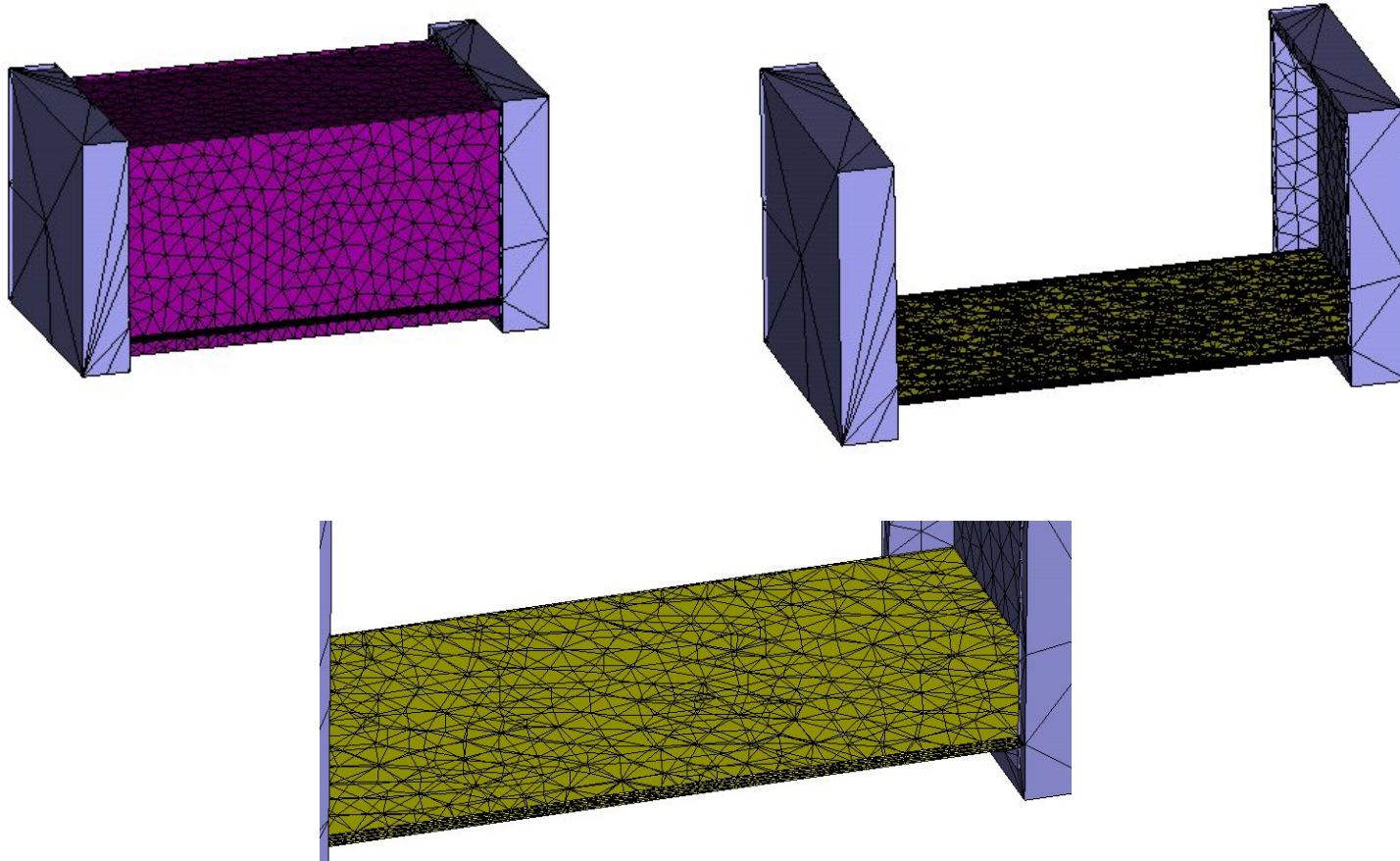
Test Fixture Model



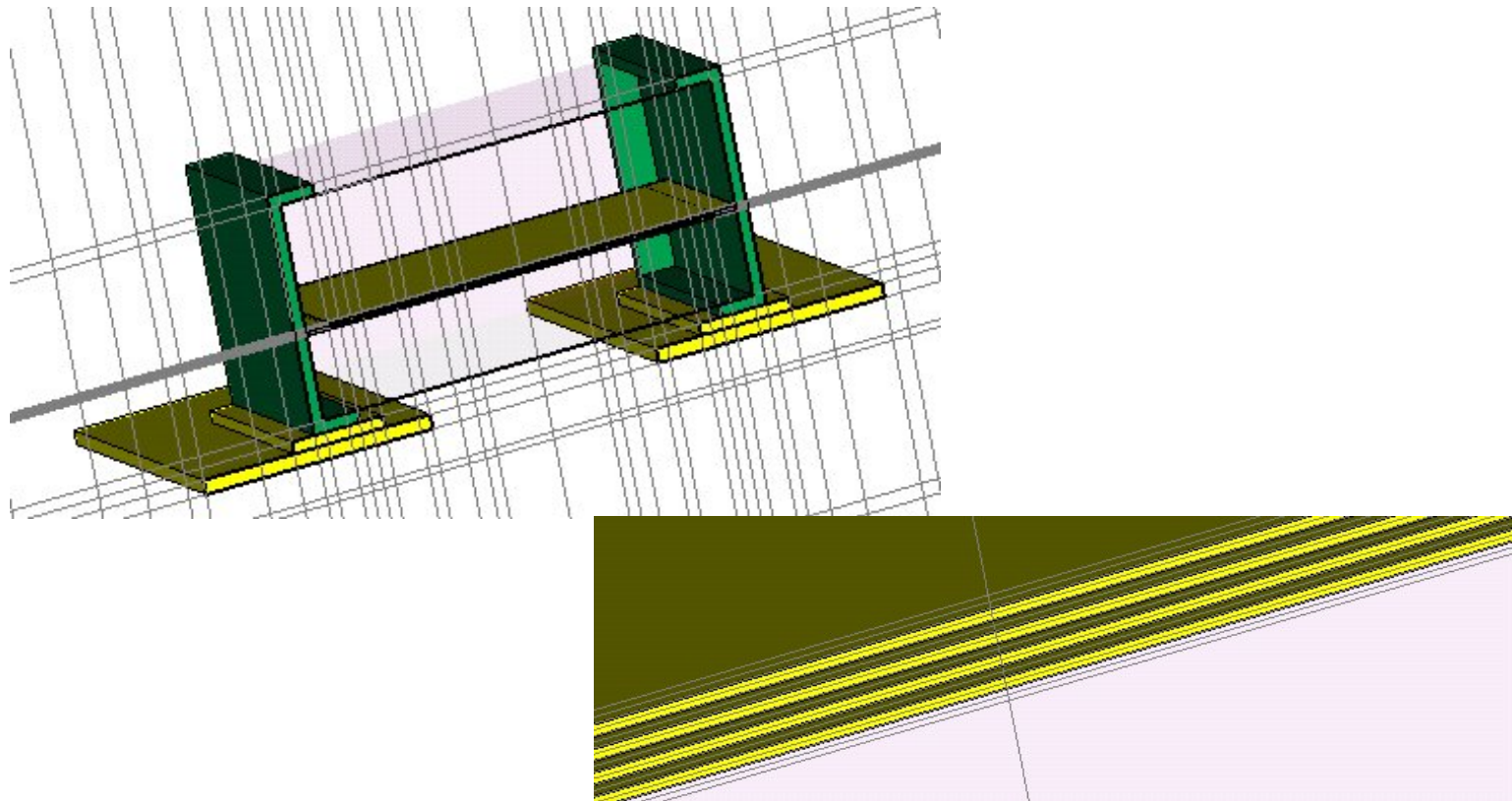
Tetrahedral mesh of test fixture



MLCC model – TET mesh

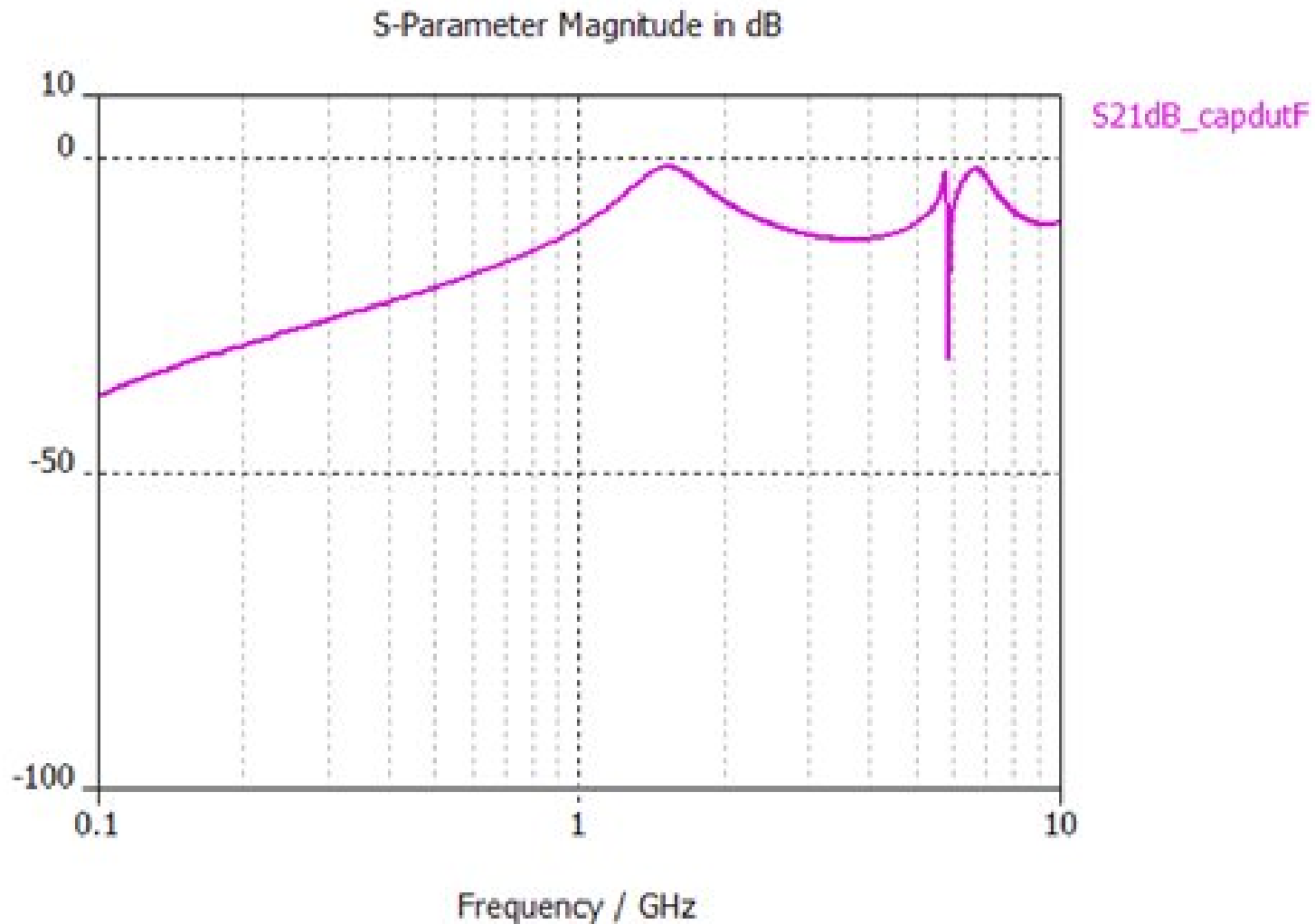


MLCC model – HEX mesh

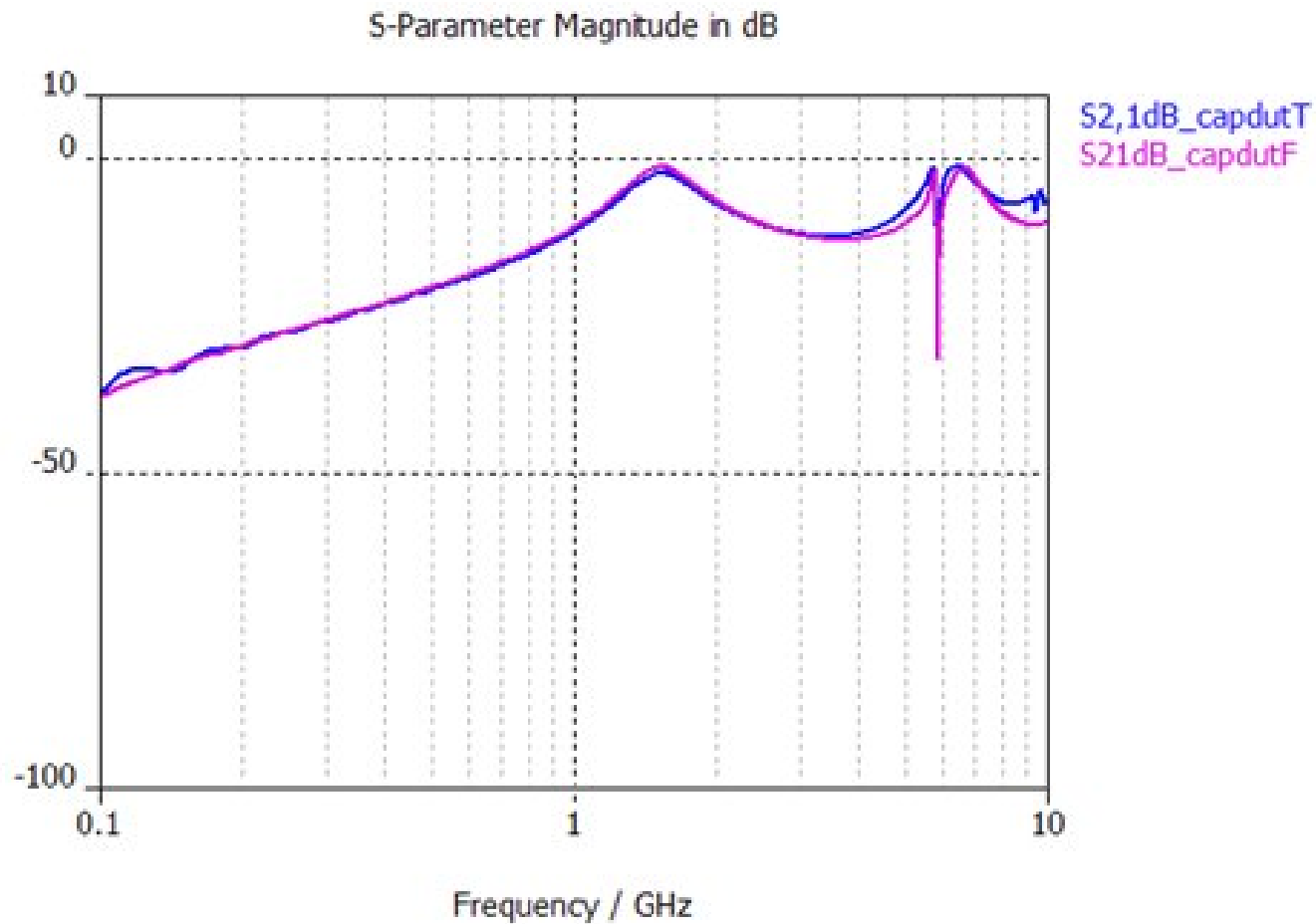


Simulation Results

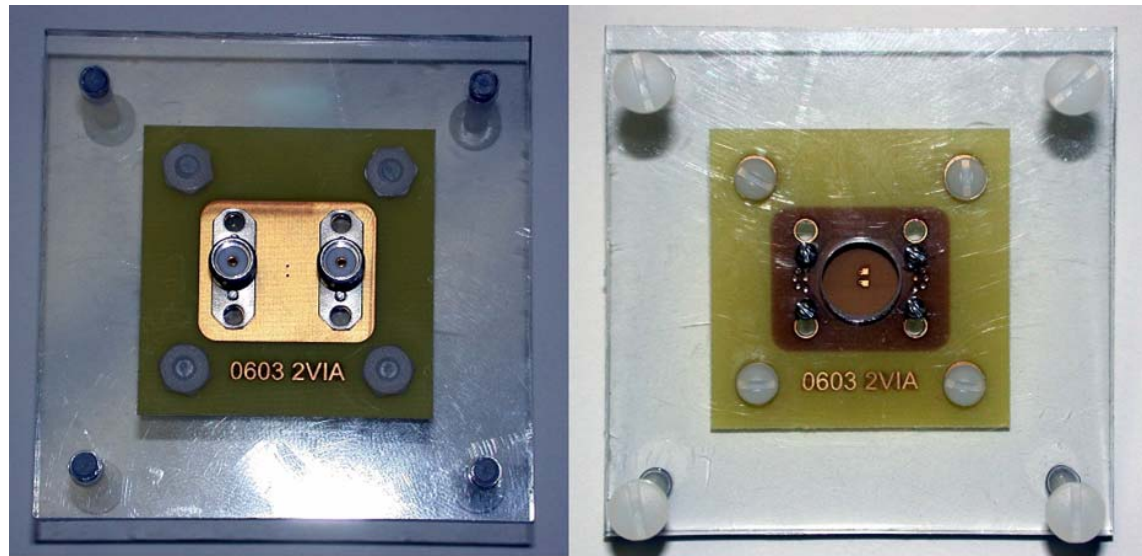
Frequency Domain Solver S21



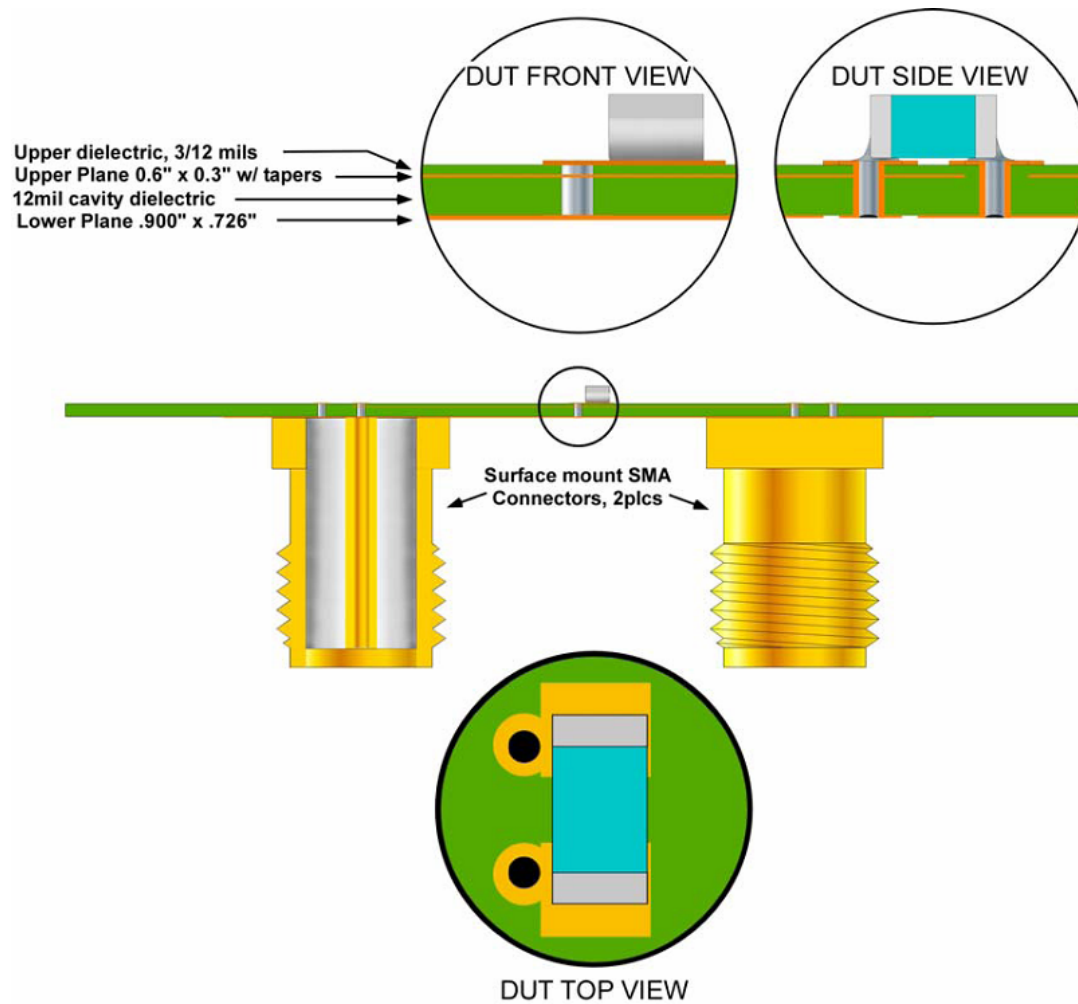
Validation between Transient and Frequency Domain Solvers



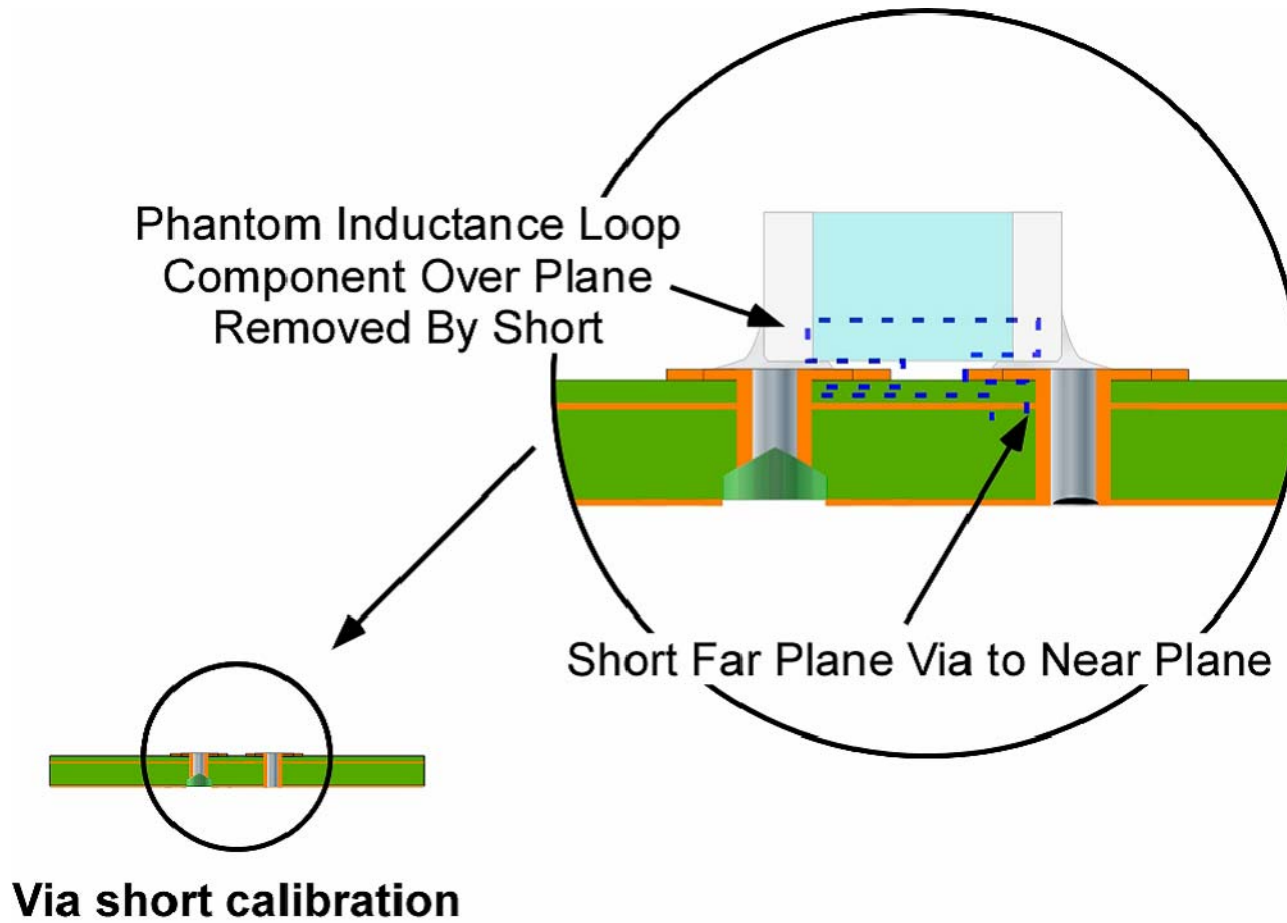
Measurement Fixture



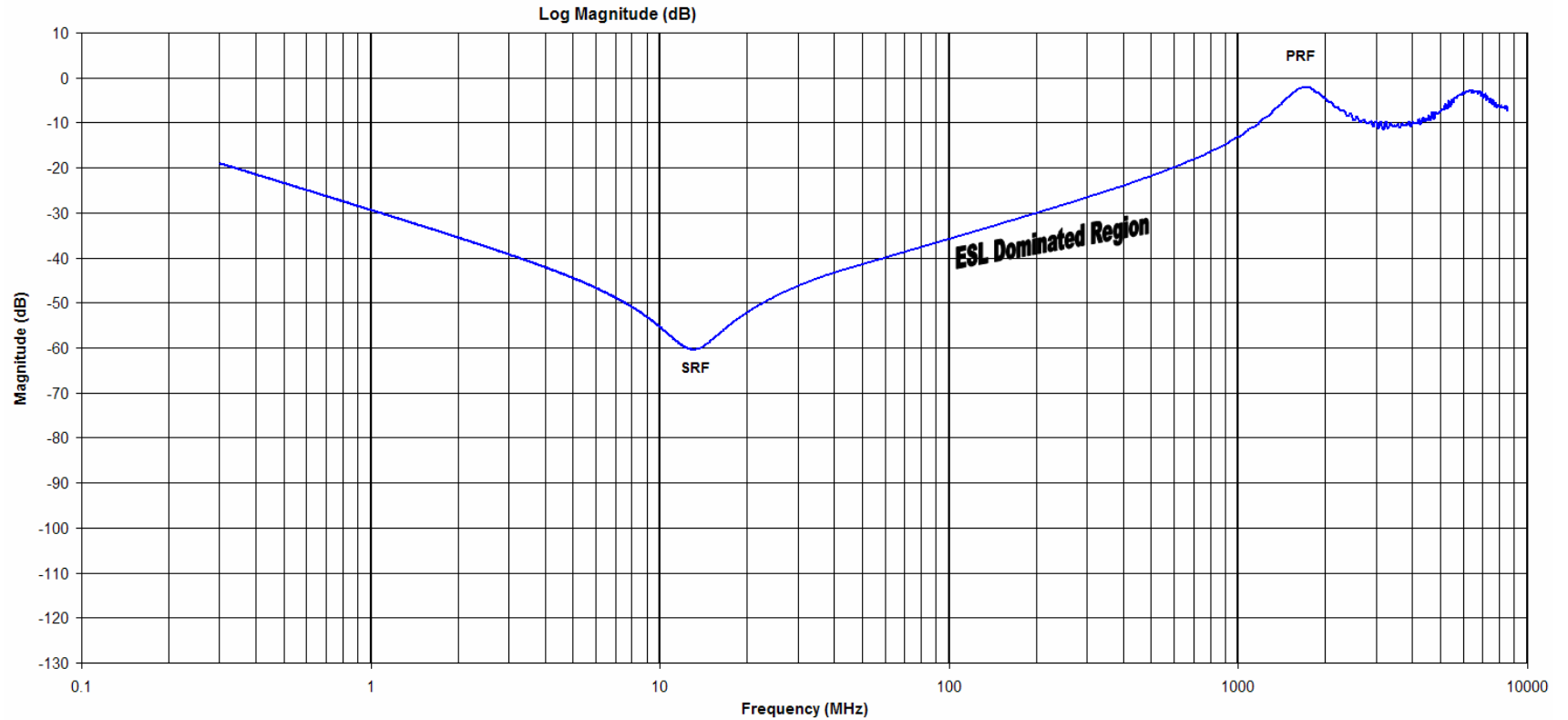
Detailed view of fixture



Via Short Calibration



Capacitor Transfer Impedance Measurement



0.22uF 0402 capacitor



Simulation and Measurement Correlation

	100 MHz	200 MHz	300 MHz	400 MHz	500 MHz
Shorted Structures					
Via Short Time Domain Solver	107 pH	106 pH	107 pH	108 pH	109 pH
Via Short Frequency Domain Solver	113 pH	112 pH	113 pH	114 pH	115 pH
Via Short Measured	86 pH	85 pH	85 pH	86 pH	88 pH
Pad Short Time Domain Solver	379 pH	342 pH	367 pH	367 pH	374 pH
Pad Short Frequency Domain Solver	403 pH	404 pH	411 pH	423 pH	439 pH
Pad Short Measured	403 pH	404 pH	411 pH	421 pH	440 pH
2 mil MLCC DUT Cover Layer					
DUT Time Domain Solver	462 pH	485 pH	515 pH	532 pH	552 pH
DUT Frequency Domain Solver	506 pH	507 pH	518 pH	535 pH	709 pH
Actual DUT Measured	658 pH	646 pH	654 pH	672 pH	707 pH
8 mil MLCC DUT Cover Layer					
DUT Time Domain Solver	662 pH	640 pH	647 pH	671 pH	704 pH
Actual DUT Measured	658 pH	646 pH	654 pH	672 pH	707 pH



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Summary & Conclusions

- o Capacitor bypass structured can be modeled effectively with 3D full wave solvers
- o Techniques have been demonstrated for accurate measurement and modeling
- o Methods can be applied to calibration of PDS full wave S-parameter simulations
- o Further validation studies ongoing.
- o Measured and corrected MLCC capacitor library under current development.

